

METHOD FOR TESTING IC CARD AND DEVICE THEREFOR

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Abstract

PROBLEM TO BE SOLVED: To provide an IC card testing technique for reducing the data transmitting time, and for speeding up test by reducing data transfer between a tester and an IC card to the minimum.

SOLUTION: At the time of data writing test to the EEPROM of a non-contact or contact type IC card, a writing data generation program and a command are transmitted from an IC card tester to the IC card (603). The IC card analyzes the command (606), and operates the command processing of the data writing test (607), and repeats data writing/reading/comparison judgment from a start address to an end address (608-613), and transmits only a final test result to an IC card tester (614). The IC card tester integrally judges the writing function test of the EEPROM based on the final test result (616).

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